

Laser Diode LIVE Tester



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Acquire light-current-voltage (LIV) curves with the measurement APIs and calculate characteristics of a laser diode (LD) with the analysis API based on the acquired LIV curves.



The LIV Test System provides the capability to assess the laser characteristics of all devices across all four measurement quadrants without the need for additional equipment.



The resulting LIV curve reveals important clues about the quality of manufacture and the performance of the laser diode, enabling a pass/fail decision to be met. To test if all functional components are ...



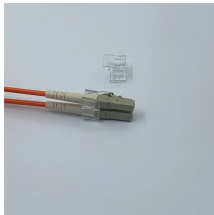
Generate high resolution LIV (light, current, voltage) curves in seconds, revealing diode performance metrics such as threshold current and slope efficiency. View the results on the modern touchscreen ...



The ideal laser diode testing system would assess all possibly relevant characteristics with high accuracy and perfect reliability within a short time, and this with high convenience and at a low cost, ...



These instruments perform complete LIV measurements in extremely short time for high throughput by using pulse testing method, QCW and CW testing including burn-in.



The LIV100 is a short pulse test system for the characterization of laser diodes and LEDs at the chip, bar or submount level. The fast rise time with essentially no overshoot allows testing these thermally ...



A light-current-voltage (LIV) test is one of the essential tests that a laser diode must go through to ensure its reliability for post production use. This test will help to verify the operating characteristics ...



Life-test and qualification test system for laser diode reliability evaluation in CW or pulsed regime down to 1 nanosecond. Up to 112 fully independent fibered devices are electrically, thermally and optically ...



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Die Tester CT8203 is for the LIV scanning and optoelectronic characteristics test of the semiconductor LD laser at low temperature and normal temperature. The system is designed with a dual ...

Contact Us

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